Se	arçn No	tes
] ([Blek libik celel		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/520,280	ARAKI, TAKAKO
Examiner	Art Unit
Linh T. Nauven	2627

	SEARCHED				
Class	Subclass	Date	Examiner		
	-				
	·		•		
					

. INT	INTERFERENCE SEARCHED		
· Class	Subclass	Date	Examiner
	·		
			ļ

(INCLUDING SEARCH		
·	DATE	EXMR
East text searched.	03/29/06	LN
	·	
		·